
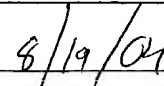
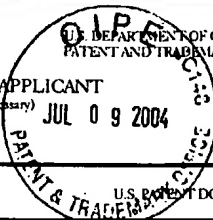


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1724	SERIAL NO. 09/905,286	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Cem Basceri et al.		
JUL 09 2004 PATENT & TRADEMARK OFFICE				FILING DATE July 13, 2001		
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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						Yes No
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	AO	EP 0 306 069 A2	03/89	EPO		
	AP	EP 0 388 957 A2	09/90	EPO		
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

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							Yes	No
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	AP	08-060347	03/96	Japan				
EF	AQ	EP 0 810 666 A1	12/97	EPO				

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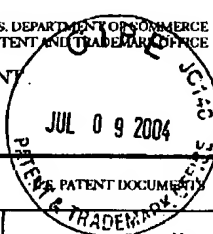
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EF	AN	JP2000091333	03/00	Japan				
EF	AO	WO 01/16395	03/01	WIPO				
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	AO						
	AP						
	AQ						

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